# MSKSEMI 美森科













**ESD** 

TVS

TSS

MOV

GDT

PLED

# NTTFS015N04C-MS

**Product specification** 





## **Description**

The NTTFS015N04C-MSuses advanced trench technology to provide excellent RDS(ON), low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### **Features**

Vps = 40V Ip =50A

 $RDS(ON) < 14m\Omega$  VGS=10V

# **Application**

- Battery protection
- Load switch
- Uninterruptible power supply

#### **Reference News**

PACKAGE OUTLINE	N-Channel MOSFET	Marking
DENEVE SI	G S	MSKSEMI S015N04C N40
DFN5X6-8L	3	

# Absolute Maximum Ratings (TC=25℃unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	40	V
Vgs	Gate-Source Voltage	±20	V
ID @Tc=25°C	Continuous Drain Current, V gs @ 10V <sup>1</sup>	50	A
Ib @Tc=100°C	Continuous Drain Current, V gs @ 10V <sup>1</sup>	38	Α
Ірм	Pulsed Drain Current <sup>2</sup>	160	Α
EAS	Single Pulse Avalanche Energy <sup>3</sup>	50	mJ
Тѕтс	Storage Temperature Range	-55 to 175	°C
TJ	Operating Junction Temperature Range	-55 to 175	°C



#### **Thermal Characteristic**

Thermal Resistance,Junction-to-Case <sup>(Note 2)</sup>	Rejc	1.76	°C/W
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# **Electrical Characteristics (TA=25℃unless otherwise noted)**

Symbol	Parameter Test Condition		Min.	Тур.	Max.	Units
Off Chara	ecteristic					
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	own Voltage V <sub>GS</sub> =0V, I <sub>D</sub> =250µA		_	-	V
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> =40V, V <sub>GS</sub> = 0V,	-	-	1	μA
lgss	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±20V	-	-	±100	μΑ
On Chara	cteristics					
$V_{GS(th)}$	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250µA	1.0	1.6	2.5	V
$R_{DS(on)}$	Static Drain-Source on-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =30A	-	11	14	mΩ
<b>g</b> FS	Forward Transconductance	VDS=5V,ID=20A	30	-	-	S
Dynamic C	Characteristics(Note 4)					
C <sub>iss</sub>	Input Capacitance		_	1540	_	pF
Coss	Output Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1.0MHz	_	171	-	pF
Crss	Reverse Transfer Capacitance	1-1.01/11/12	_	115	-	pF
Switching	Characteristics(Note 4)			ı	1	
t <sub>d(on)</sub>	Turn-on Delay Time		-	5	-	ns
<b>t</b> r	Turn-on Rise Time	V <sub>DD</sub> =20V, I <sub>D</sub> =20A,RL=1Ω	-	24	-	ns
t <sub>d(off)</sub>	Turn-off Delay Time		-	38	-	ns
<b>t</b> f	Turn-off Fall Time	$V_{GS}$ =10V, $R_{GEN}$ =3 $\Omega$	-	12	-	ns
Qg	Total Gate Charge	\/ 00\/ 1 00A	-	24	-	nC
Qgs	Gate-Source Charge	V <sub>DS</sub> =30V, I <sub>D</sub> =30A, V <sub>GS</sub> =10V	-	5.9	-	nC
$Q_{gd}$	Gate-Drain Charge		-	3.6	-	nC
Drain-So	urce Diode Characteristics and	Maximum Ratings	-			
ls	Drain Forward Current <sup>(Note 2)</sup>		_	_	48	А
VsD	Drain Forward Current(Note 3)	V <sub>GS</sub> =0V, I <sub>S</sub> =30A	-	-	1.2	V
trr	Reverse Recovery Time	TJ=25°C, IF=30A	-	9	-	ns
Qrr	Reverse Recovery Charge	di/dt=100A/µs <sup>(Note 3)</sup>	-	15	-	nC
ton	Forward Turn-On Time Intrinsic turn-on time is negligible(turn-on is dominated br LS+LD					LS+LD

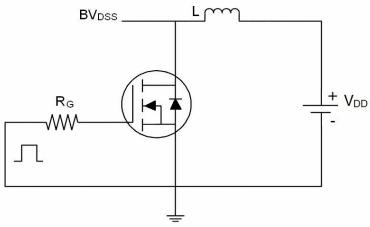
#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t≤10 sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle≤2%.
- 4. Guaranteed by design, not subject to production
- 5. Eas condition: Tj=25  $^{\circ}$ C,VDD=30V,VG=10V,L=0.5mH,Rg=25 $\Omega$

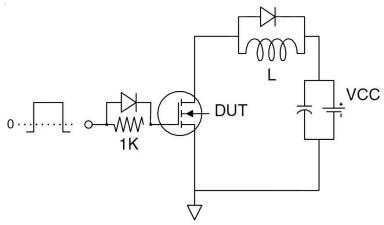


#### **Test circuit**

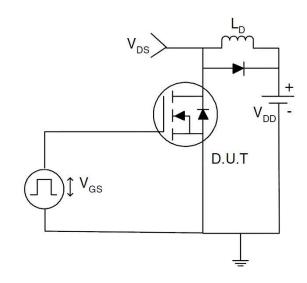
## 1) E<sub>AS</sub> test Circuits



## 2) Gate charge test Circuit



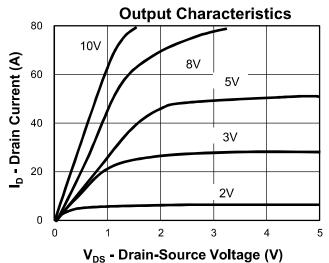
#### 3) Switch Time Test Circuit

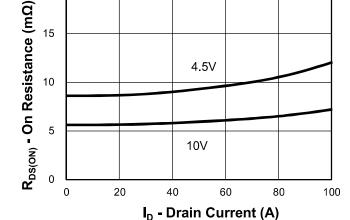


**Drain-Source On Resistance** 

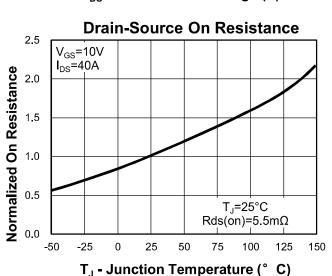


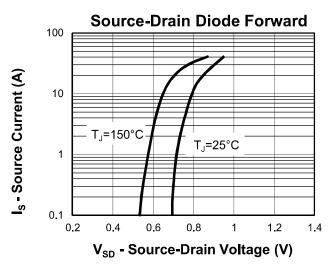
# **Typical Characteristics**

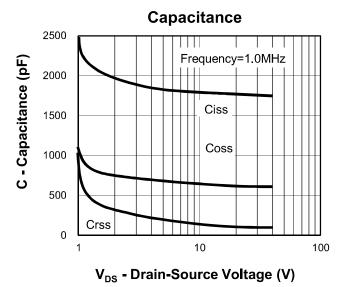


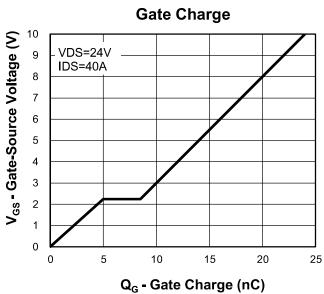


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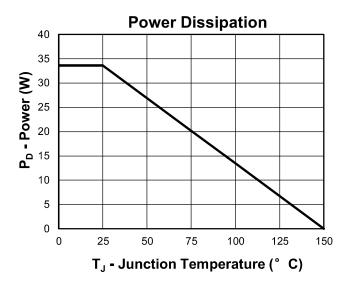


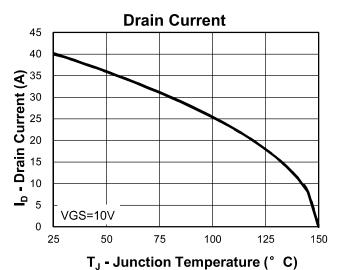


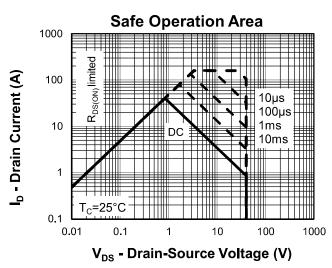


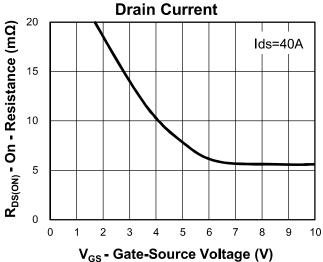


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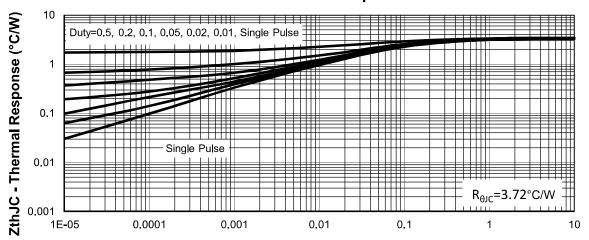








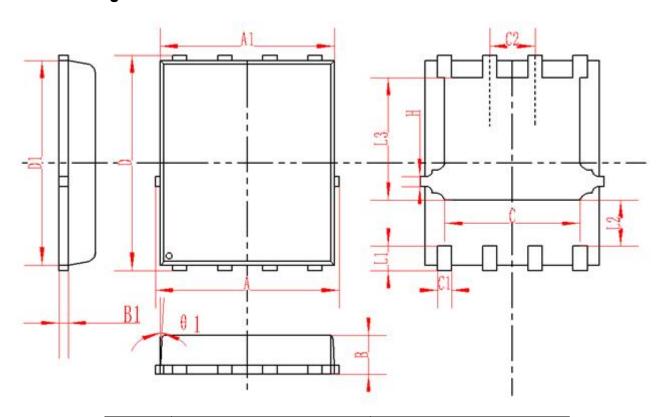
#### **Thermal Transient Impedance**



**Square Wave Pulse Duration (sec)** 



# DFN5X6-8L Package Information



SYMBOL	MM		INCH			
STIVIDUL	MIN	NOM	MAX	MIN	NOM	MAX
А	4.95	5	5.05	0.195	0.197	0.199
A1	4.82	4.9	4.98	0.190	0.193	0.196
D	5.98	6	6.02	0.235	0.236	0.237
D1	5.67	5.75	5.83	0.223	0.226	0.230
В	0.9	0.95	1	0.035	0.037	0.039
B1	0.254REF		0.010REF			
С	3.95	4	4.05	0.156	0.157	0.159
C1	0.35	0.4	0.45	0.014	0.016	0.018
C2	1.27TYP		0.5TYP			
θ1	8。	10 <sub>°</sub>	12 <sub>°</sub>	8。	10 <sub>°</sub>	12。
L1	0.63	0.64	0.65	0.025	0.025	0.026
L2	1.2	1.3	1.4	0.047	0.051	0.055
L3	3.415	3.42	3.425	0.134	0.135	0.135
Н	0.24	0.25	0.26	0.009	0.010	0.010

# **REEL SPECIFICATION**

P/N	PKG	QTY
NTTFS015N04C-MS	DFN5X6-8L	5000



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